



## Hall effect detection of optically invisible defects in CVD graphene

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# Hall effect detection of optically invisible defects in CVD graphene

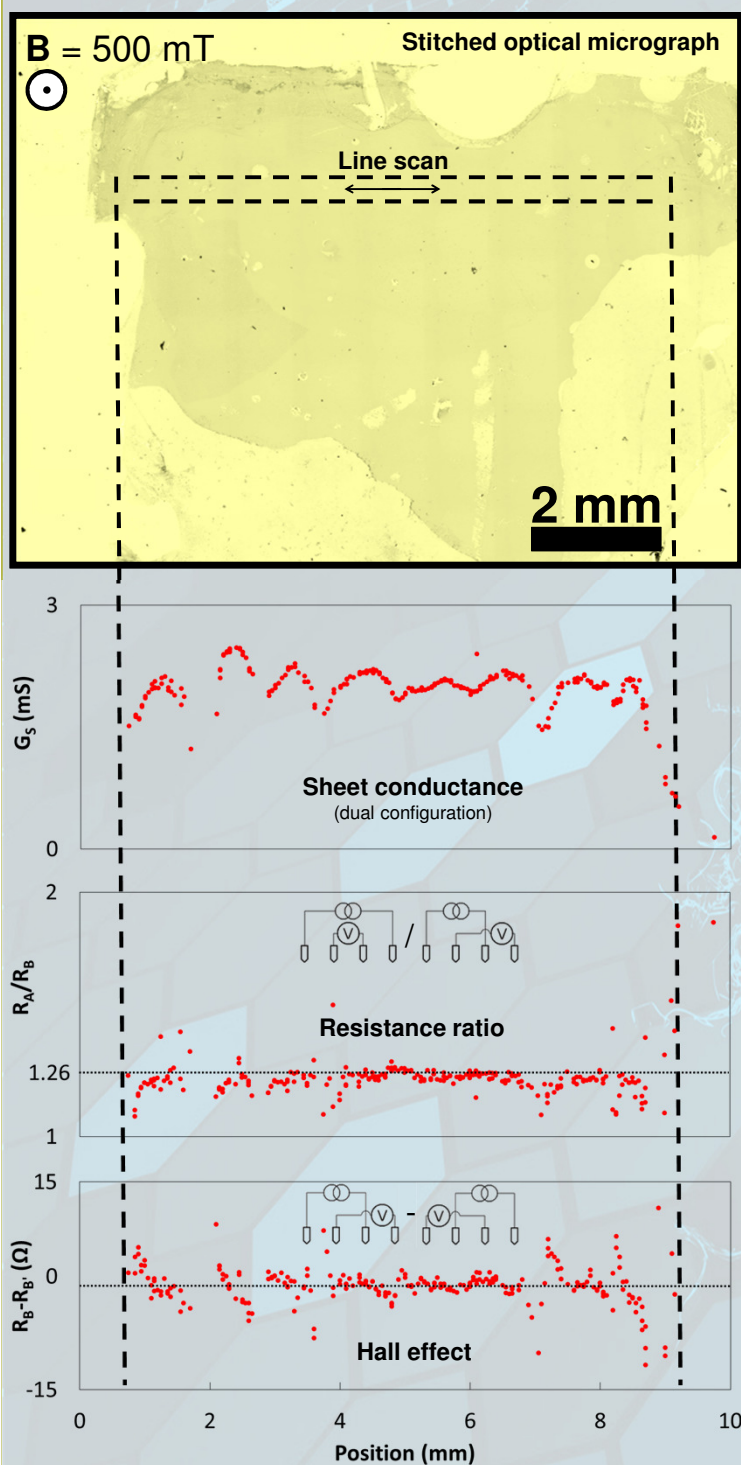
D.H. Petersen, B.S. Jessen, F. Pizzocchero, D. Kjær, H.H. Henrichsen, O. Hansen, P. Bøggild

Presenting author

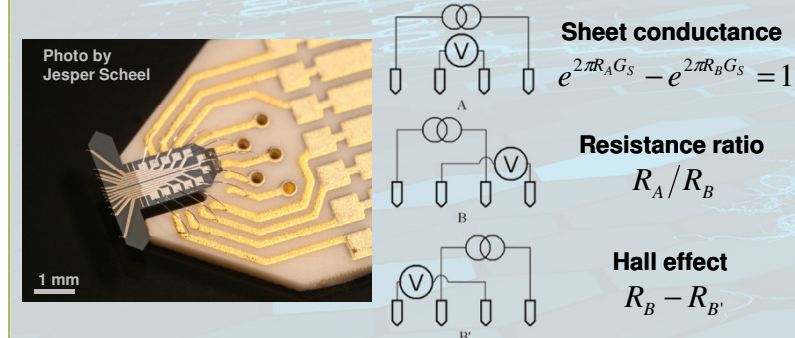


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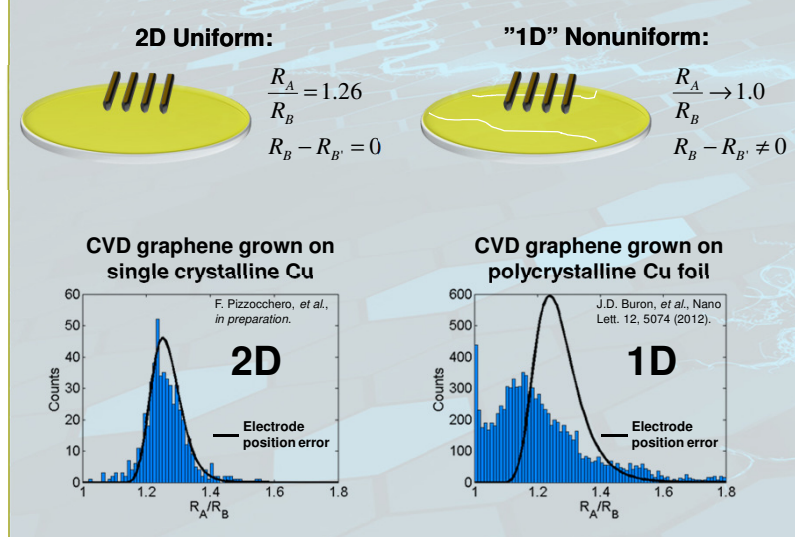
## CVD graphene quality



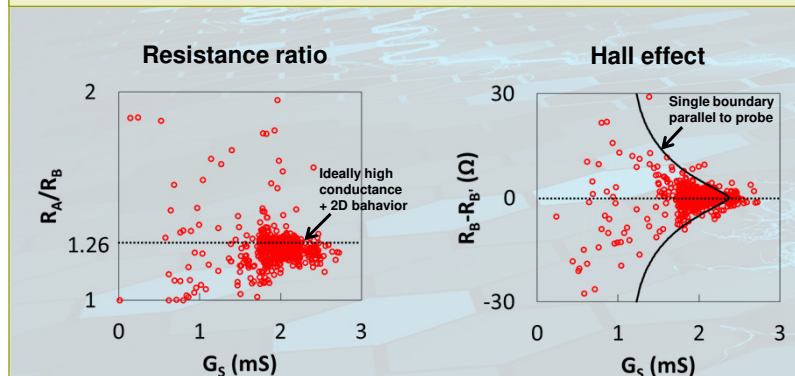
## Micro four-point probe



## Electrical continuity



## Conductance / defect correlation



## Sensitivity to electrically insulating line defects

